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| Notice of References Cited | Application/Control No. 09/987,766 | Applicant(s)/Patent Under Reexamination STEINBERG ET AL. | |
| | Examiner Daniel E Valencia | Art Unit 2874 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------|----------------|
| | A | US-6,340,251 | 01-2002 | Shibuya et al. | 385/89 |
| | B | US-6,222,967 | 04-2001 | Amano et al. | 385/49 |
| | C | US- | | | |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|---------------|----------------|
| | N | JP 11305151 A | 11-1999 | Japan | TAMURA et al. | G02B 26/08 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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